

Description

Silicon Carbide (SiC) Schottky Diodes use a completely new

FFSB20120A

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Value	Unit	
V _{RRM}	Peak Repetitive Reverse Voltage	1200	V	
E _{AS}	Single Pulse Avalanche Energy (Note 1)	200	mJ	
I _F	Continuous Rectified Forward Current @ T _C < 157°C	20	A	
	Continuous Rectified Forward Current @ T _C < 135°C	32		
I _{F, Max}	Non-Repetitive Peak Forward Surge Current	T _C = 25°C, 10 μs	1190	A
		T _C = 150°C, 10 μs	990	A
I _{F, SM}	Non-Repetitive Forward Surge Current	Half-Sine Pulse, t _p = 8.3 ms	135	A
I _{F, RM}	Repetitive Forward Surge Current	Half-Sine Pulse, t _p = 8.3 ms	74	A
P _{tot}	Power Dissipation	T _C = 25°C	333	W
		T _C = 150°C	55	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +175	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. E_{AS} of 200 mJ is based on starting T_J = 25°C, L = 0.5 mH, I_{AS} = 29 A, V = 50 V.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
R _{θJC}	Thermal Resistance, Junction to Case, Max	0.45	°C/W

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V _F	Forward Voltage	I _F = 20 A, T _C = 25°C				

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TYPICAL CHARACTERISTICS

TEST CIRCUIT AND WAVEFORMS

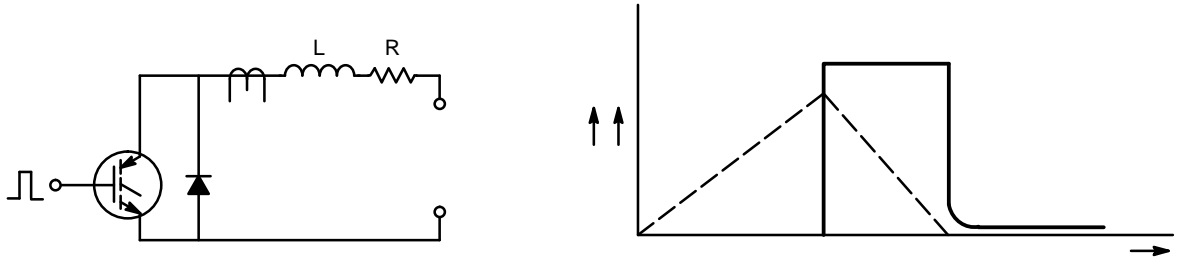
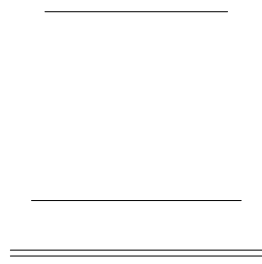
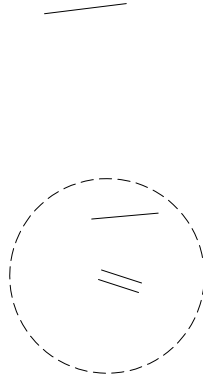


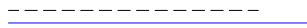
Figure 9. Unclamped Inductive Switching Test Circuit & Waveform

D²PAK2 (TO-263-2L)
CASE 418BK
ISSUE O

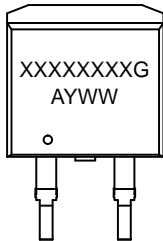
DATE 02 AUG 2018



DET/



**GENERIC
MARKING DIAGRAM***



- XXX = Specific Device Code
- A = Assembly Location
- Y = Year
- WW = Work Week
- G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

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